Form PTO-1449 *(Substitute)*	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number ANRI-08064US1	Application Number ~~New Application~~ 10/641,700
INFORMATION DISCLOSURE STATEMENT BY APPLICANT *(Use several sheets if necessary)*		Applicant Jon S. Martens et al.	
		Filing Date August 15, 2003	Group Art Unit 2863 ~~New Application~~

U.S. PATENTS

Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
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Examiner	John Le	Date Considered	01/07/05

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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